

Search Notes

Application/Control No.

10/048,007

Examiner

Yuwen Pan

Applicant(s)/Patent under
Reexamination

WATANABE ET AL.

Art Unit

2682

SEARCHED

Class	Subclass	Date	Examiner
455	404.1,404. 2,412.2, 414.4,	9/14/2004	YW
	419		
	423		
	66.1		
UPDATE	SEARCH	8/10/2005	YW
UPDATE	SEARCH	12/29/2005	YW

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner